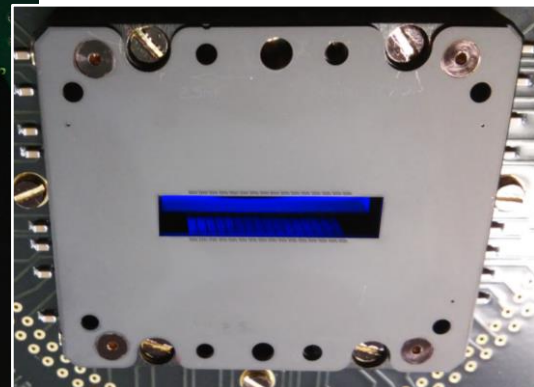
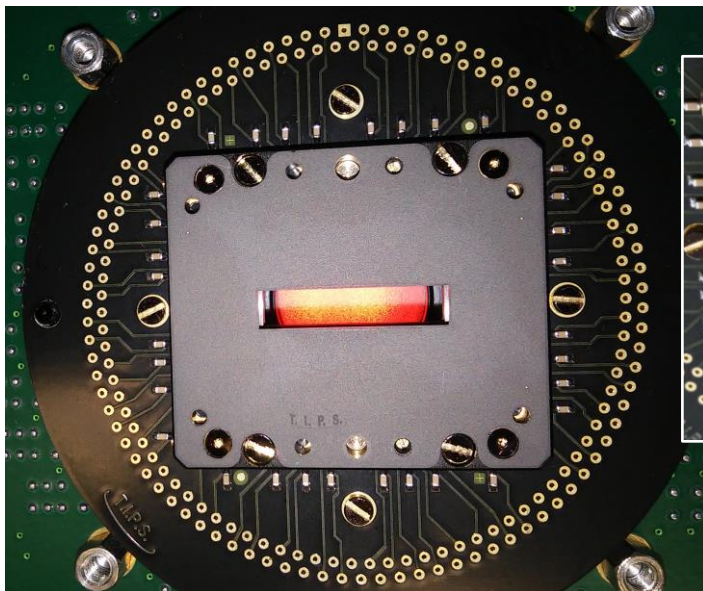


Probe Cards for Optical Sensors (Colour, Automotive LIDAR, X-Ray Imagers...)

State-of-the-art contacting technologies, tailored for excellent contact performance for various chip technologies are combined with sensor stimuli to allow for precise measurements on wafer level for optical sensors.

Contactor geometries and materials are ranging from vertical probe card technologies to high performance cantilever technologies, both for laboratory tests and high volume production wafer test.



Vertical Probe Card for
Optical Colour Sensor

Cantilever Probe Card for
X-ray imaging sensor
featuring high-voltage
bias supply

